Se	arcn Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/043,047	YOO ET AL.	
Examiner	Art Unit	
Tse Chen	2116	

SEARCHED					
Class	Subclass	Date	Examiner		
			,		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			

SEARCH NOT	ES					
	(INCLUDING SEARCH STRATEGY)					
	DATE	EXMR				
INVENTOR MAME	1/17/09	TSE				
text search only; "STUB", "MEMORY", "CLOCK"	1/17/07	156				
713/500 & 713/600 WM4 "STUB"	417/07	756				